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Multi-layer ceramic chip capacitors MCH18 (1608 (0603) size, chip capacitor)

Features

- 1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
- Comes packed either in tape to enable automatic mounting or in bulk cases.
- Precise uniformity of shape and dimentions highly efficient automatic mounting.
- Barrier layer and end terminations to improve solderability.











Capacitance range

For thermal compensation

Part nur	MCH18	
	Temperature characteristics	A (CG) (C0G)
Capacitance(pF)	Rated voltage Tolerance (V)	50
0.5 0.75 1		
1.1 1.2 1.3		
1.5 1.6 1.8		
2 2.2 2.4	C (± 0.25pF)	
2.7 3 3.3		
3.6 3.9 4		
4.3 4.7 5		
5.1 5.6 6		
6.2 6.8 7		
7.5 8 8.2	D (±0.5pF)	
9 9.1 10		
11 12 13		
15 16 18		
20 22 24		
27 30 33	$1(\pm 50)$	
36 39 43	J (±5%)	
47 51 56		
62 68 75		
82 91 100		





High dielectric constant

Part num	nber			MCH18		
	Temperature characteristics	CN (R) (B) (X7R)		FN (F) (Y5V)		
oupuolianoo(pr)	Rated voltage (V)	50	25	50	25	16
	Tolerance	K (±	10%)	Z	(+80%, –20	%)
220						
330						
390		~~~~~				
470 560						
680						
820						
1,000						
1,200						
1,500						
2.200		××××		××××		
2,700						
3,300						
3,900		×××××		NYXXXX		
4,700						
6.800						
8,200						
10,000 (0.01µF)						
12,000		RXXXXXX				
18,000						
22.000						
27,000						
33,000						
39,000			xxxxxx	xxxxxx		
56.000						
68,000						
82,000						
100,000 (0.1µF)						
120,000						
180,000						
220,000						
270,000						
330,000						
390,000 470,000						
560,000						
680,000						
1,000,000 (1µF)						
1,200,000						
1,500,000						
2,200,000						

Product thickness (mm) 0.8 ± 0.1



Characteristics

Class 1 (For thermal compensation)

Temperature characteristics Item		A (CG) (C0G)	Test methods / conditions (based on JIS C 5102)	
Operating temperature		−55°C ~ +125°C		
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity. 1000pF or less Measurement frequency : 1± 0.1MHz Measurement voltage :1± 0.1Vrms. Over 1000pF Measurement frequency : 1± 0.1Vrms. Measurement voltage :1± 0.1Vrms.	
Dissipation factor $(\tan \delta)$		100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)		
Insulation resistance (IR)		10,000M\Omega or $500M\Omega{\cdot}\mu F$, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 \pm 5s.	
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.	
Temperature characteristics		Within 0 \pm 30ppm / $^{\circ}$ C	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20° C and high temperature.	
Terminal adhe	adherence No detachment or signs of detachment. Based on paragraph 8.11.2 in the direction indicated by the arrow.		Based on paragraph 8.11.2 Apply 5N for 10 ± 1s in the direction indicated by the arrow.	
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	to vibration (type A in paragraph 8.2),	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	and measured 24 ± 2 hrs. later. Board	
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	$\begin{array}{ll} \text{Based on paragraph 8.13} \\ \text{Soldering temperature} &: 235 \pm 5^\circ \text{C} \\ \text{Soldering time} &: 2 \pm 0.5 \text{s} \end{array}$	
	Appearance	There must be no mechanical damage.		
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF , whichever is larger.	Based on paragraph 8.14	
Resistance to soldering	Dissipation factor (tano)	Must satisfy initial specified value.	Soldering temperature : 260 ± 5°C Soldering time 5 + 0.5s	
heat	Insulation resistance	10,000M\Omega or 500M\Omega μF , whichever is smaller	Preheating $: 150 \pm 10^{\circ}$ C for	
	Withstanding voltage	The insulation must not be damaged.	1.02 mm.	
	Appearance	There must be no mechanical damage.		
Temperature cycling	Rate of capacitance change	\pm 2.5% \pm 0.25 pF , whichever is larger.	Based on paragraph 9.3 Number of cycles : 5 Capacitance measured after 24 ± 2 hrs.	
	Dissipation factor (tanδ)	Must satisfy initial specified value.		
	Insulation resistance	10,000M\Omega or 500M\Omega μF , whichever is smaller		
Humidity load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF , whichever is larger.	Test temperature : 40 ± 2°C Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 trs.	
	Dissipation factor (tanδ)	0.5% or less		
	Insulation resistance	500M Ω or 25M $\Omega\cdot\mu F$, whichever is smaller	Capacitance measured after 24 \pm 2 hrs.	
	Appearance	There must be no mechanical damage.	Based on paragraph 9 10	
High-	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF , whichever is larger.	Test temperature : Max. operating temp.	
temperature load test	Dissipation factor (tan)	0.3% or less	Test time : 1,000 to 1,048 hrs.	
	Insulation resistance	1,000MΩ or 50MΩ· μ F , whichever is smaller	Capacitance measured after 24 ± 2 hrs.	



Class 2 (High die	ectric constant)				
Temperature characteristics		CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Item		EE90 112590	20%0		
Operating temp	perature	-55°U ~ +125°U	-30"C ~ +80"C		
Nominal capac	itance (C)	Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humidity,	
Dissipation facto	or (tanδ)	2.5% or less (when rated voltage is 16V: 3.5% or less)	5.0% or less (when rated voltage is 16V: 7.5% or less)	Measurement frequency: 1 \pm 0.1 kHz Measurement voltage $$: 1.0 \pm 0.2 Vrms.	
Insulation resistance (IR)		10,000 MΩ or 500 MΩ $\cdot\mu\text{F},$ whichever is smaller		Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.	
Withstanding v	Withstanding voltage The insulation must not be damaged.		st not be damaged.	Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure.	
Temperature c	haracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C, with no voltage applied.	
Terminal adherence		No detachment or signs of detachment		Based on paragraph 8. 11. 2. Apply 5N for 10 ± 1s in the direction indicated by the arrow. End to the direction of the di	
	Appearance	There must be no m	nechanical damage.	Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within	initial tolerance.	manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
	Dissipation factor (tan b)	Must satisfy initia	al specified value.	and measured 48 ± 4 hrs. later. Board	
Solderability	Solderability At least 3/4 of the surface of the two terminals must be covered with new solder		ninals must be covered with new solder.	Based on paragraph 8. 13 Soldering temperature: $235 \pm 5^{\circ}$ C Soldering time : $2 \pm 0.5s$	
	Appearance	There must be no m	nechanical damage.		
	Rate of capacitance change	Within ± 5.0%	Within ± 20.0%	Denod an appropriate 9, 14	
Resistance to soldering	Dissipation factor (tanb)	Must satisfy initia	al specified value.	Soldering temperature: 260 ± 5°C	
heat	Insulation resistance	10,000M\Omega or 500M\Omega $\cdot\mu\text{F},$ whichever is smaller			
	Withstanding voltage	The insulation must not be damaged.		l	
	Appearance	There must be no m	nechanical damage.		
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3	
cycling	Dissipation factor (tan b)	Must satisfy initia	al specified value.	Capacitance measured after 48 ± 4 hrs.	
	Insulation resistance	10,000MΩ or 500MΩ · ;	μF, whichever is smaller	l	
	Appearance	There must be no m	nechanical damage.	Resed on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C	
Humidity load test	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500MΩ or 25MΩ · μF	, whichever is smaller	Capacitance measured after 48 ± 4	
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10	
High- temperature load test	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature: Max. operating ter Applied voltage : rated voltage × 20 Test time : 1,000 to 1,048 hrs Capacitance measured after 48 ± 4 h	
	Insulation resistance	1,000M Ω or 50M $\Omega \cdot \mu'$	F, whichever is smaller		









MCH18

Ceramic capacitors

•Electrical characteristics



■CN (X7R) Characteristics



TEMPERATURE : (°C)

Fig.5 Capacitance - temperature

characteristics







■FN (Y5V) Characteristics 20

10 C (%)

-10

-80

-80 -40 0 40 80 120 160

CAPACITANCE CHANGE : -20 -30 -40 -50 -60 -70

*The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

Dissipation factor (%)

50 40

30 20

10



MCH18

Ceramic capacitors











Humidity load test



Fig.31 Rate of capacitance change

Fig.33 Insulation resistance

*The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



Fig.32 tano